

Search Notes	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/533,556	PARK, JOON-YOUNG
Examiner	Art Unit	
Jinhee J. Lee	2831	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
174	as above	12/12/2005	LEE
361	as above	12/12/2005	LEE